



LAUROC1

Liquid Argon Upgrade Read Out Chip

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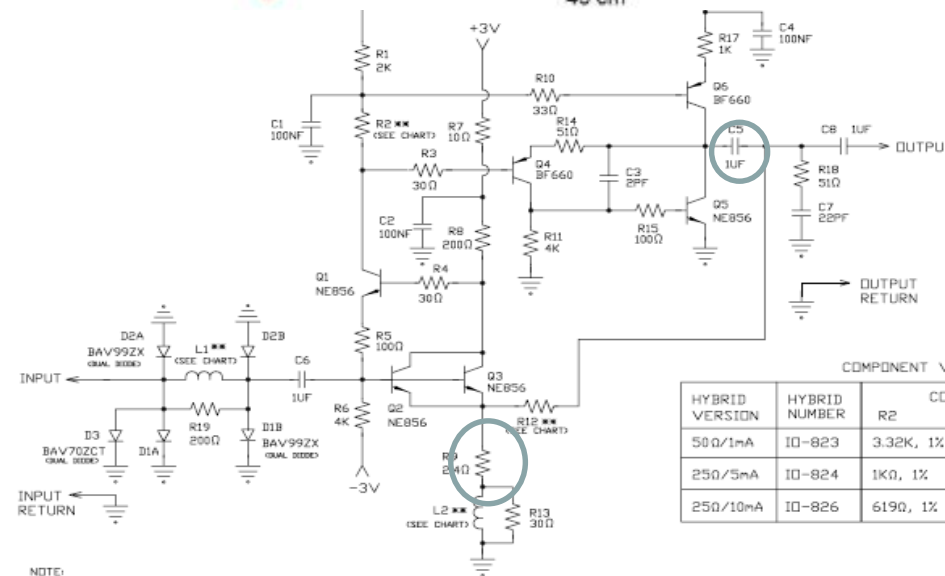
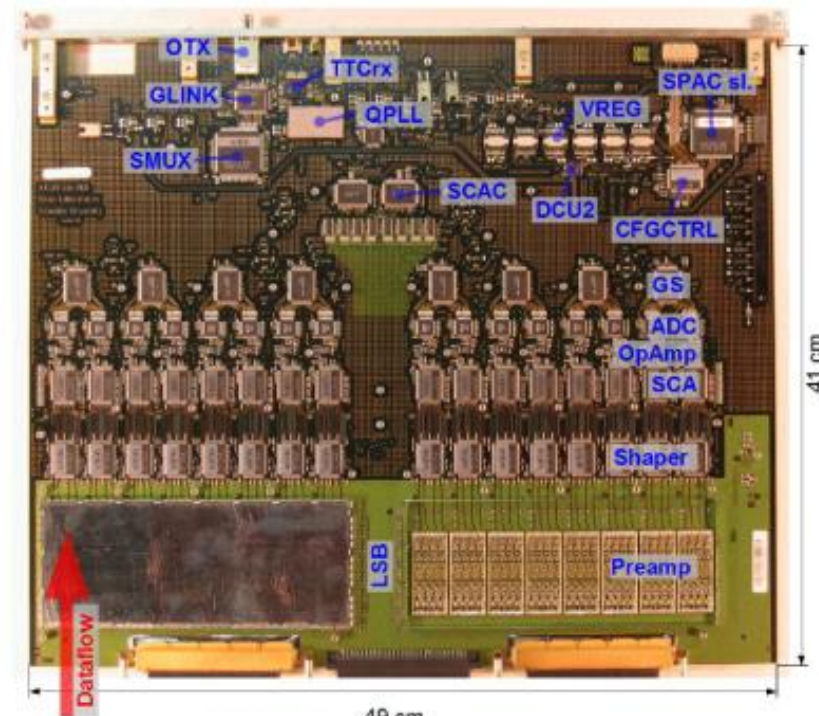
BNL : H. Chen, M. Dabrovski H. Liu

- LAUROC : liquid Argon Upgrade Read Out Chip
- Aurochs ['ɔ:ɾɔks] : extinct species of Wild Ox
- Strong and bullish
- [Astérix en Hispanie]
- Suggested by Claude Colledani !



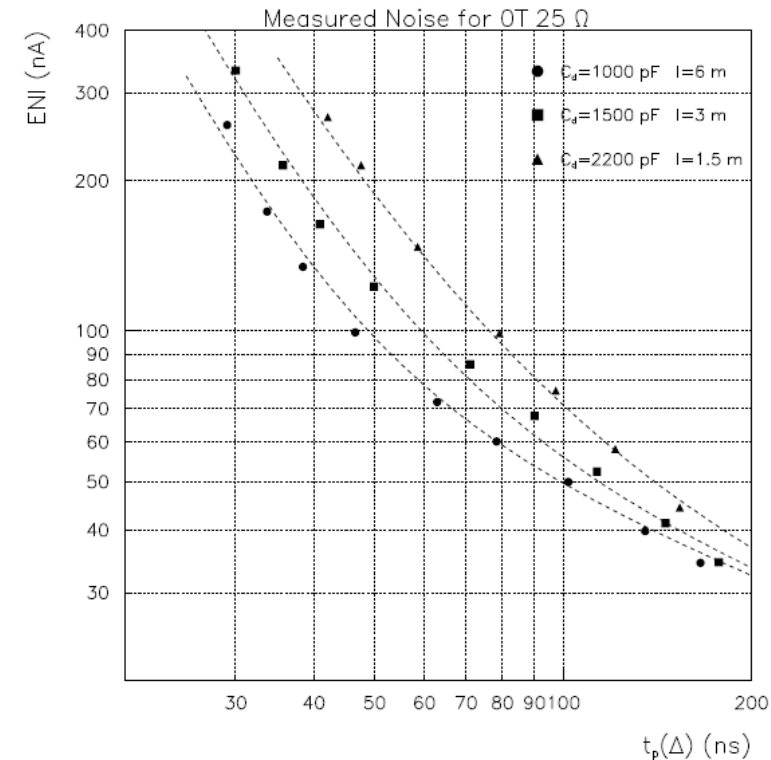
Context : ATLAS Liquid Argon calorimeter upgrade

- New design to speed up the digitization up to 40MHz and remove analog memories and obsolete components
- Replace preamps and shapers (and ADCs, SCAs, Glink...)
- Hybrid preamps used (0T configuration) → precise input impedance
 - Very low noise ($\sim 0.4 \text{ nV}/\sqrt{\text{Hz}}$)
 - Large supplies -6 +12 V
 - Some precision components and uF capacitors
 - 3 flavours : 'A', 'B', 'D'
- Shapers used AMS 1.2um BiCMOS



Preamplifier requirements

- Precise input impedance : $Z_{in} = 50 \Omega$ (Front) or 25Ω (Middle/Back) to terminate the cables from the detector
- Low noise $< 10 \Omega$, with $C_d = 400 \text{ pF}$ (Front) or 1.5 nF (Middle/Back)
- Current sensitive configuration (large C_d , long duration signal) $t_p = 50 \text{ ns}$
 - $ENI^2 = \alpha \frac{e_n^2 C_d^2}{t_p^3(\Delta)} + \beta \frac{i_n^2}{t_p(\Delta)}$ where Δ is a triangle
 - OT50 400pF: $ENI@50\text{ns}=55\text{nA}$, OT25 1.5nF: $ENI@50\text{ns}=150\text{nA}$
 - Spec : $< 120 \text{ nA}$ for 50Ω and $ENI < 300 \text{ nA}$ for 25Ω (pileup dominating at HL LHC)
- Dynamic range:
 - Front 50Ω : from 50 nA noise up to $2 \text{ mA} = 40\,000$ or 15.5 bits
 - Middle and back 25Ω : from up 200 mA to $10 \text{ mA} = 50\,000$ or 16 bits
- Radiation resistance : $\sim 1 \text{ Mrad}$
 - “Universal” preamplifier with selectable dynamic range and input impedance (25/50 Ohm)



- Integrates 8 channels with variants of preamp: PA 25 and 50 Ohms as well as a preamp 25-50 for which Z_{in} can be selected by SC

- Preamp Input impedance
 - Super Common Gate: low input impedance
 - Fine tuning of Z_{in} ($\pm 5\%$) possible with C2

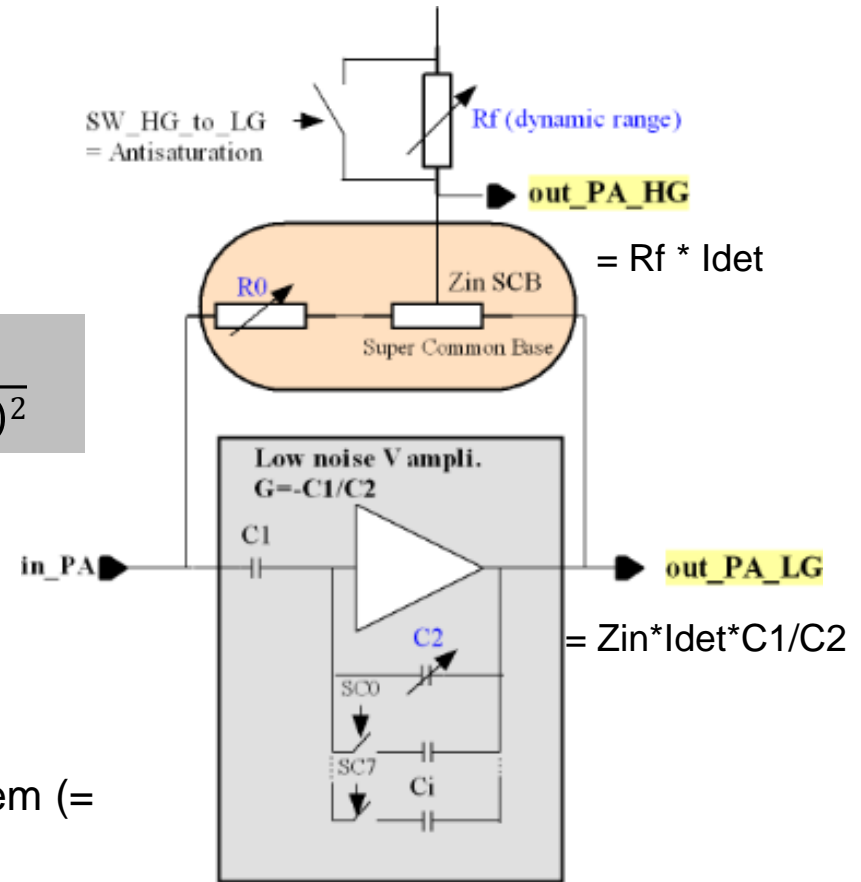
- Noise :
 - Amplifier = low noise voltage sensitive
 - **“Electronically cooled” resistor**

- HG and LG outputs available :
 - Discriminator at the output of the LG PA used to short R_f and to avoid saturation of the HG

- ⇒ This system generates some non linearity
- ⇒ Lauroc1 built around this preamp “PA_25_50” but wo the discri system (= wo the HG output)

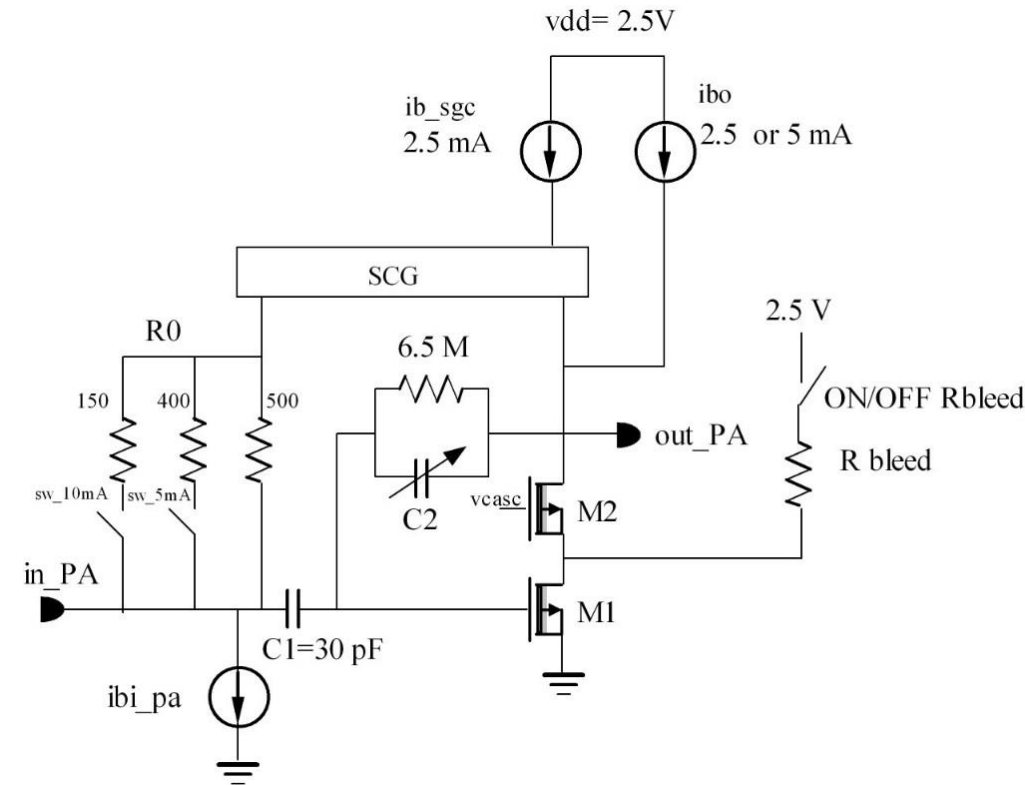
$$Z_{in PA} = \frac{R_0 + Z_{in}(SCB)}{1 + |G|}$$

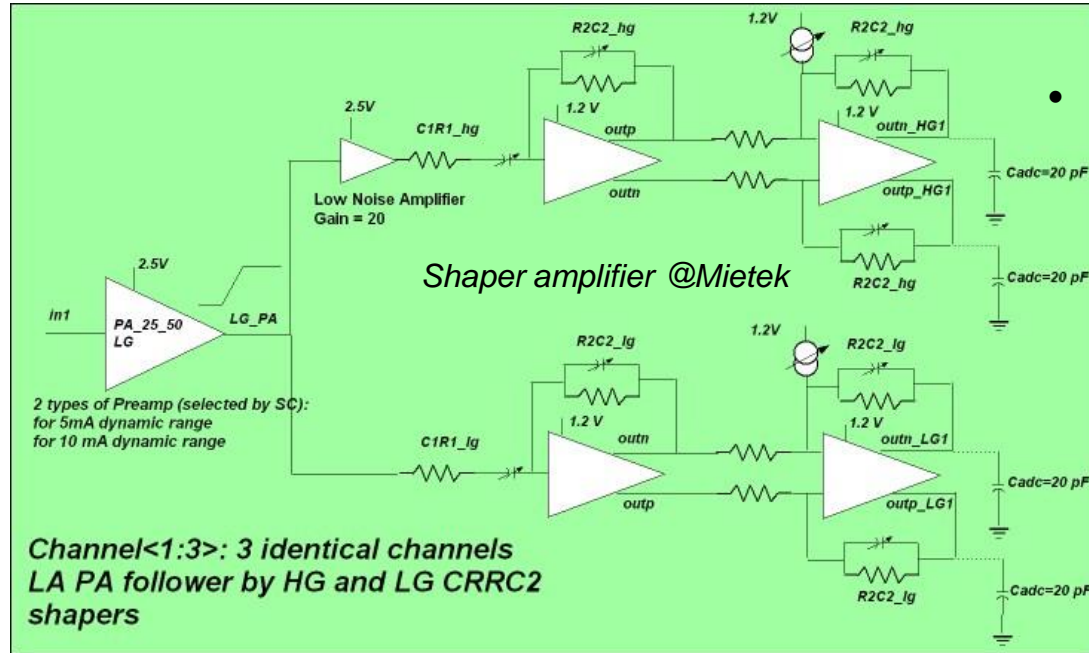
$$\frac{4kTR_0}{(1 + |G|)^2}$$



R_0 , C2 tunable to set absolute value of Z_{in}
 C_i : 8-bit fine adjustment of Z_{in} ($\pm 5\%$)
 using Slow Control parameters

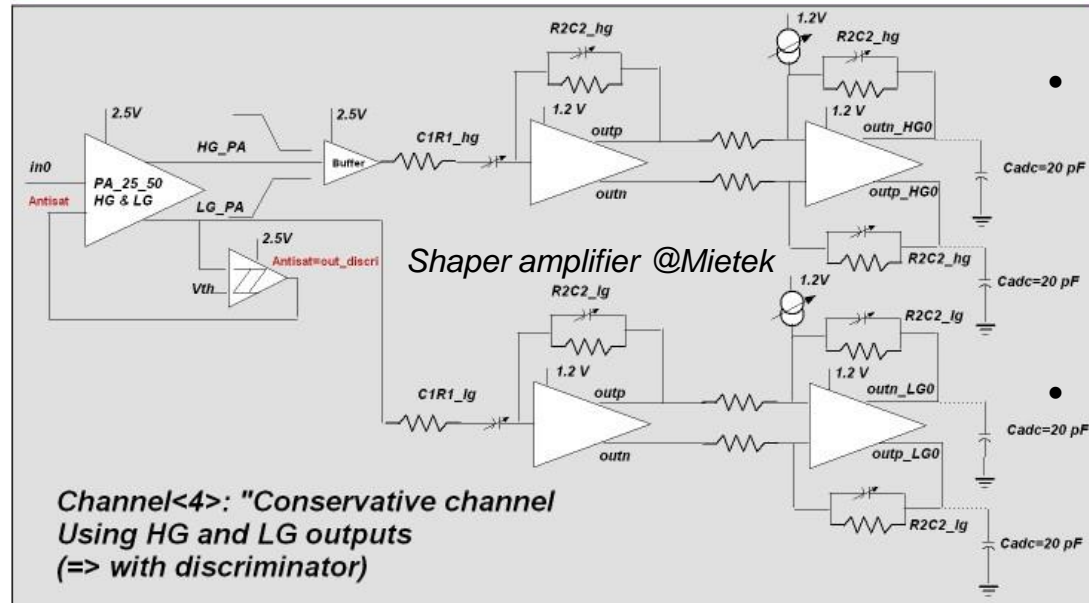
- Input transistor = 1V NMOS transistor, $3000 \mu\text{m} / 0.25 \mu\text{m}$
- Cascode trans: 2.5V NMOS transistor
- Dynamic range adjustable by R0
- Input impedance adjustment by Cf (8 bits)
- Possibility to tune the current that flows in the input preamp
 - i_{bo_pa} can be set to 2.5 mA or 5 mA using SC parameter
 - R_bleed : can add 6 mA using SC parameter





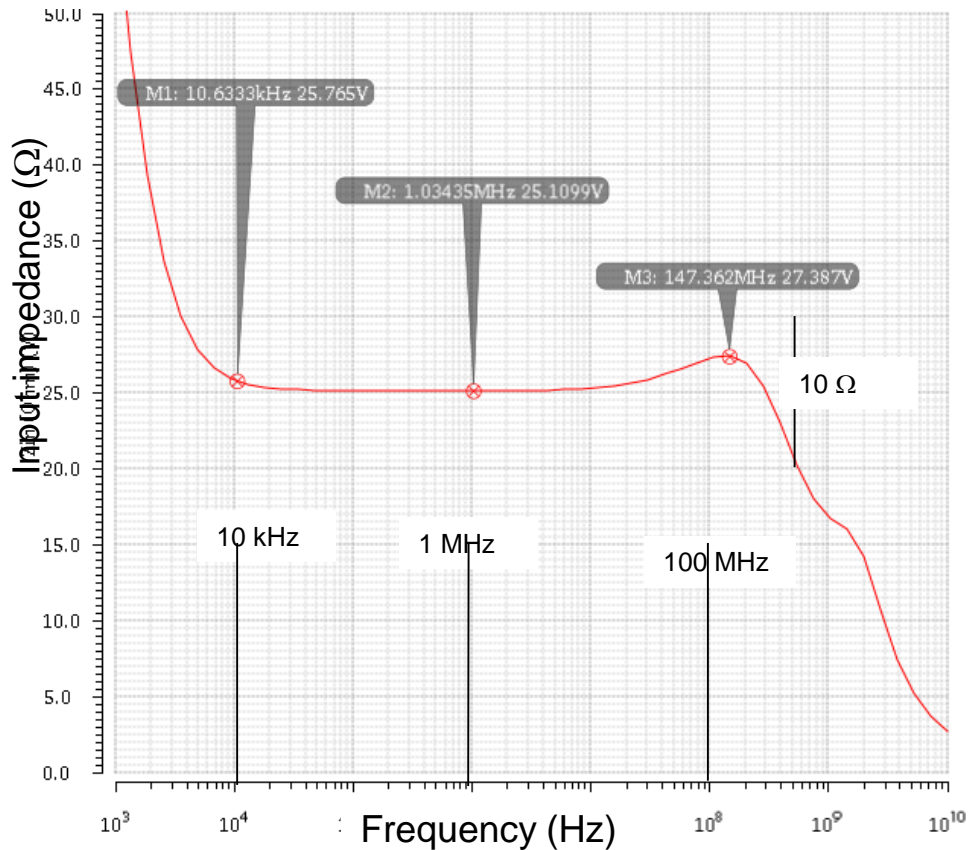
- 4 channels using the preamp_25_50 of Lauroc0 (Zin tuneable by SC)

- Channel 1, 2 and 3: LG preamp followed by one CRRC2 HG shaper and one CRRC2 LG shaper
- Channel 4: conservative channel using the discriminator and HG and LG PA for comparison



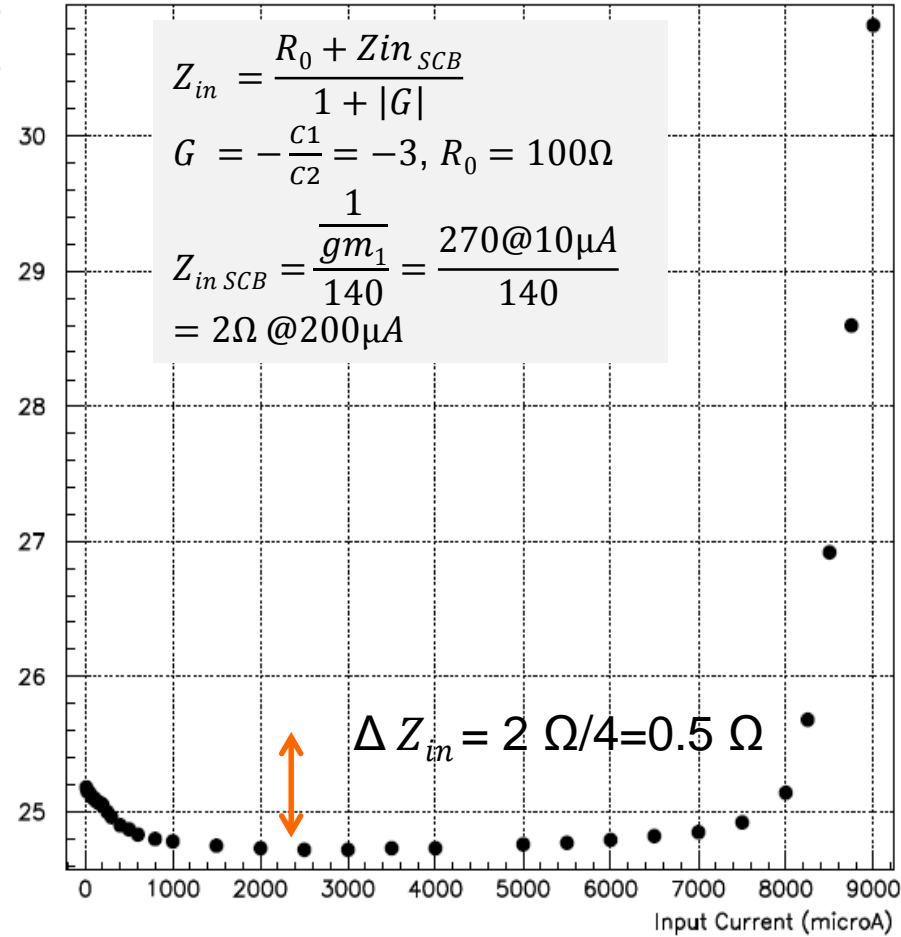
- Preamps followed by CRRC2 shapers built around an amplifier: designed by Mietek Dabrowski @BNL

- τ tuneable between 1.25 ns and 20 ns



Impedance flat from 10 kHz to 100 MHz
 < 1 Ω variation versus current due to
 Super Common base Zin variation

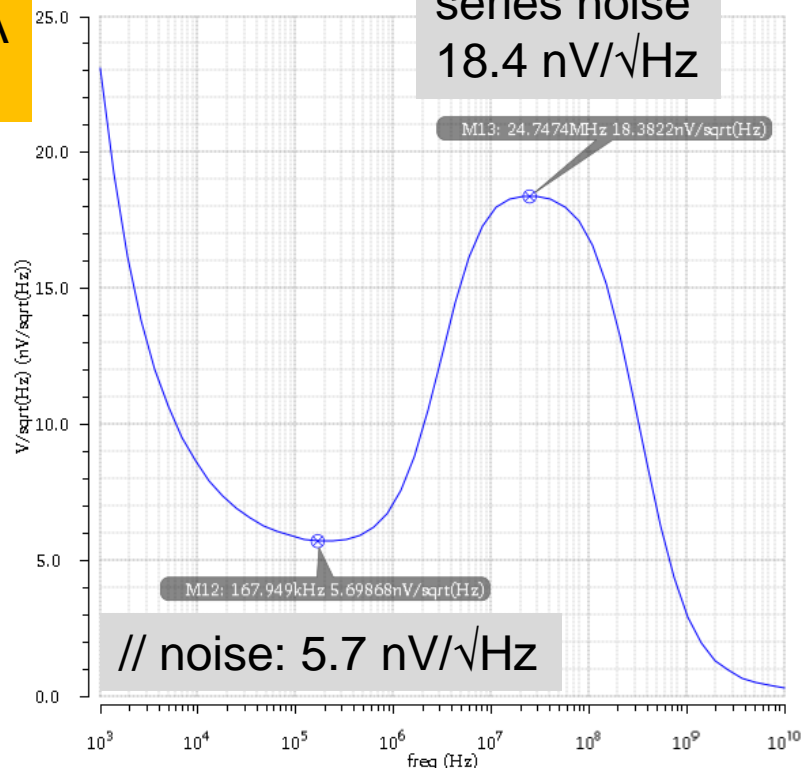
Zin simulation



HG 25 Ω PA: Equivalent Output Noise

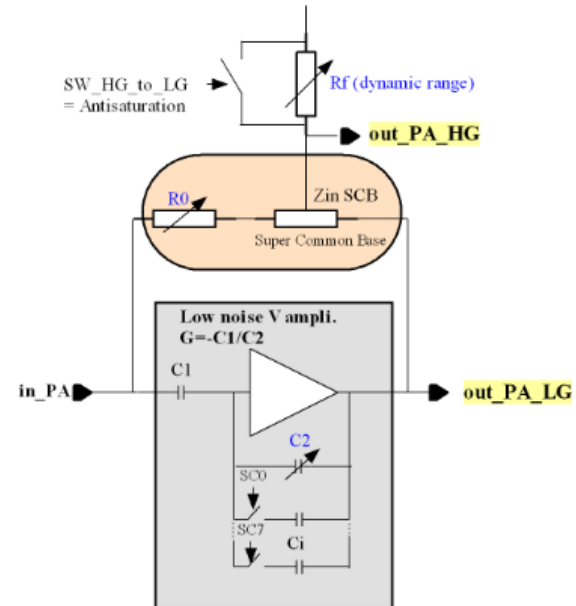
Noise Response

out_HG_PA
Cd=1.4 nF



$$\frac{4kTR_0}{(1+|G|)^2} \text{ with } G=-3$$

$R_0=100 \Omega \Rightarrow$
Equ. Noise: 0.32 nV/√Hz or 6.25Ω



R0, C2 tunable to set absolute value of Zin
Ci: 8-bit fine adjustment of Zin (±5%)
using Slow Control parameters

// noise dominated by
 $R_f=1K$ (51%)
 $R_{deg}=15K$ (26%)

Series noise:
 $R_0=100$ (43%)
NMOS ampli (24%)
NMOS SCB amp (8%)

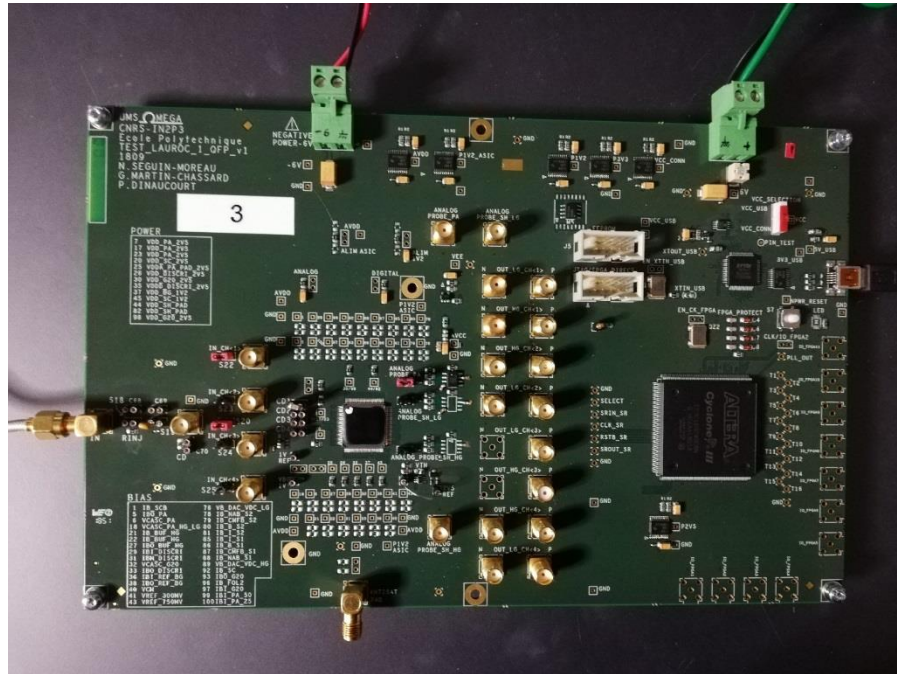
\Rightarrow Gain at the output of the preamp = $1K/25=40$
 \Rightarrow Input Noise:
 $18.4 \text{ nV}/40=0.46 \text{ nV}/\sqrt{\text{Hz}}$ or 13 Ω

2 setups:

Omega testboard (characterization)

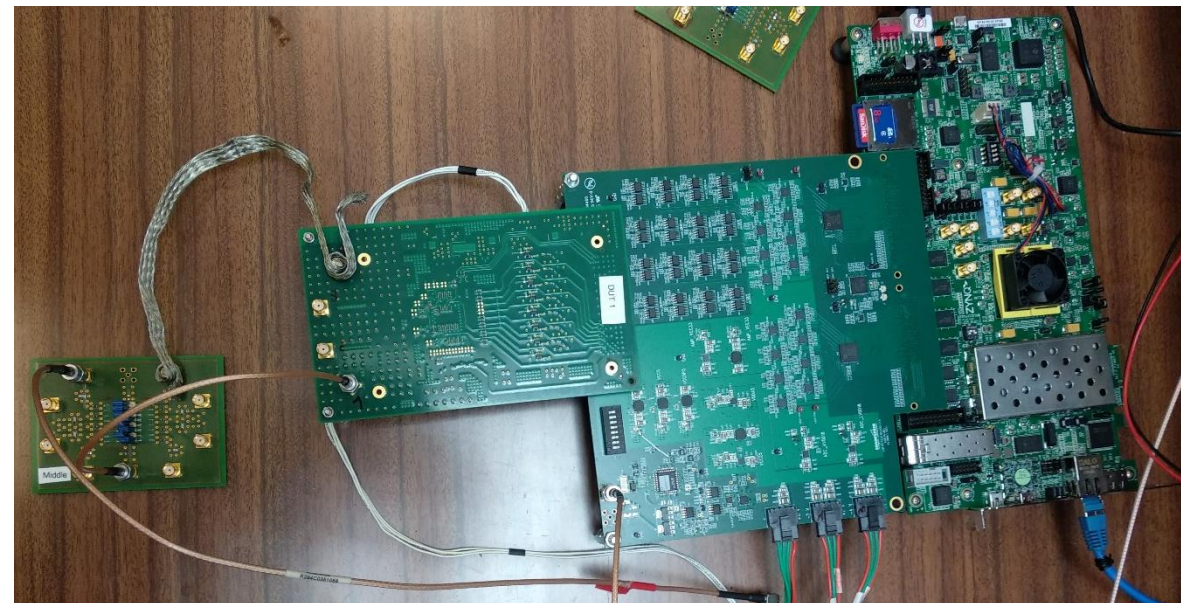
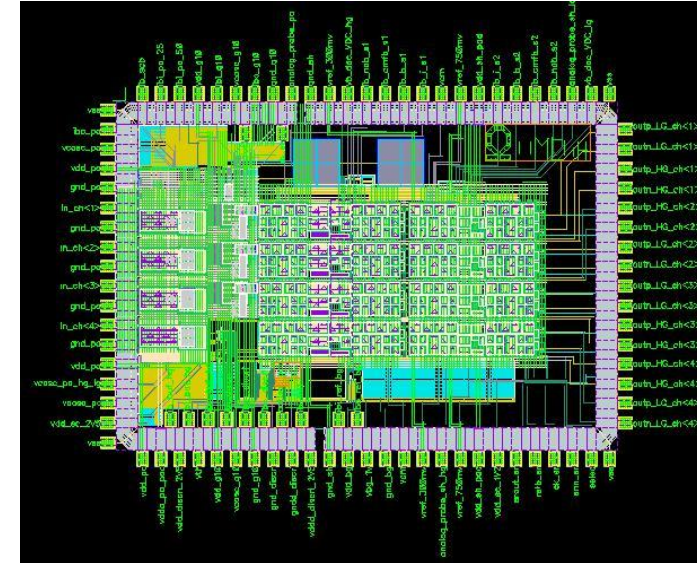
LAL/BNL setup= Injection board (Toy cal. board)+ external Pulser (Larg Pulse) + DUT + ADC

Measurements performed on scope and using the full chain (with ADC)

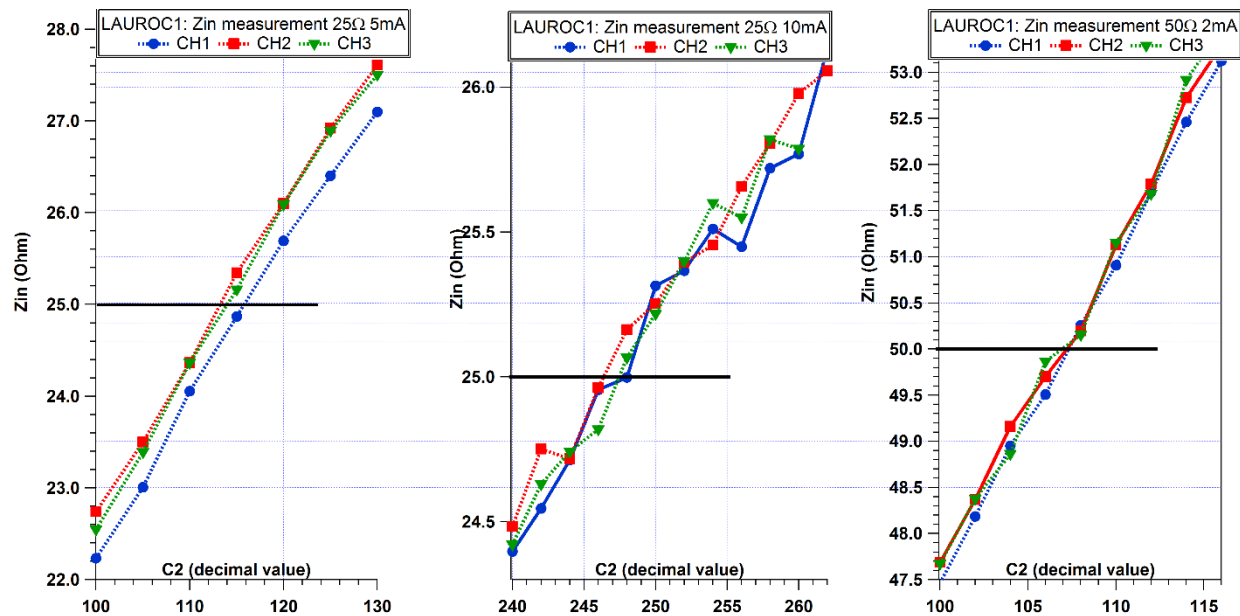


The chip size is 2.8 mm x 2.5 mm.

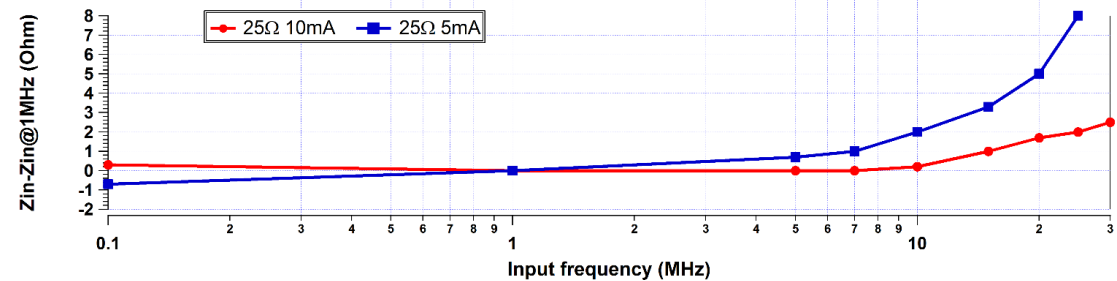
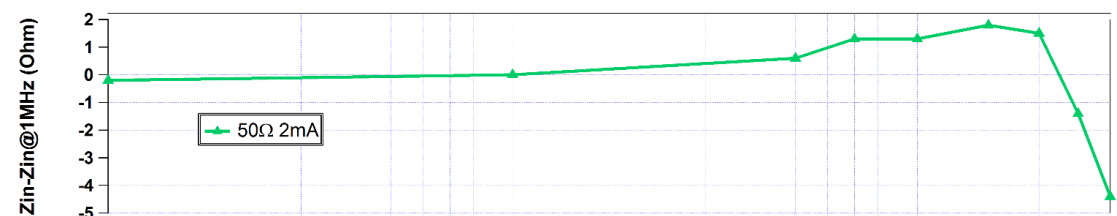
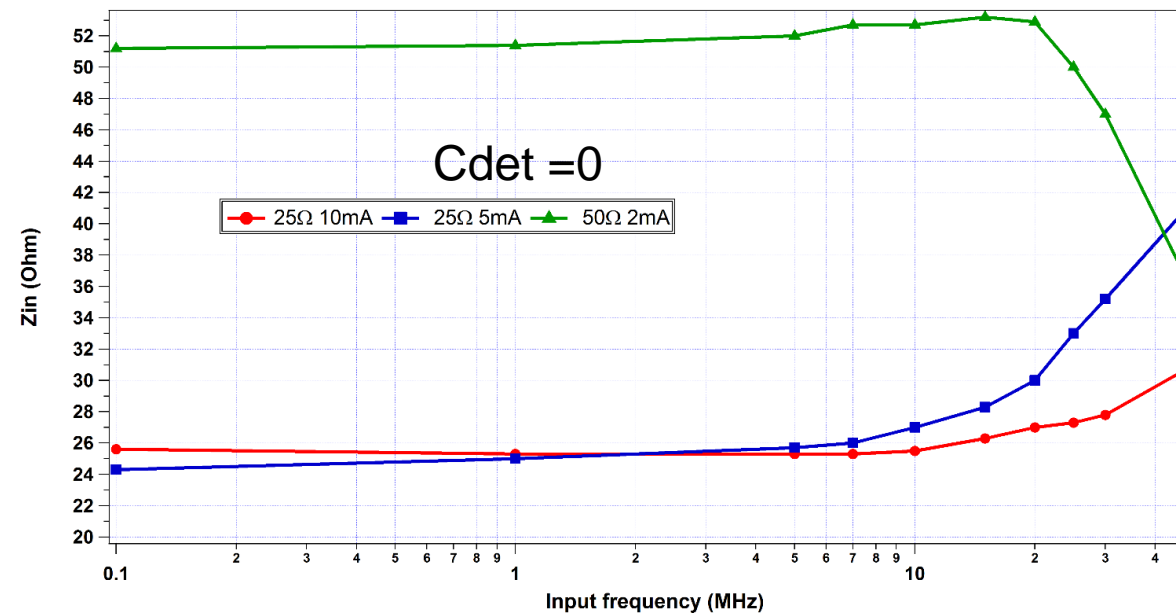
Packaged in a LQFP 100 14*14 package.



Specification: Zin tunable, $25 \pm 2.5 \Omega$ and $50 \Omega \pm 5 \Omega$ up to 20 MHz



Zin vs C2 (9 bits, LSB = 31.6 fF) for 3 channels



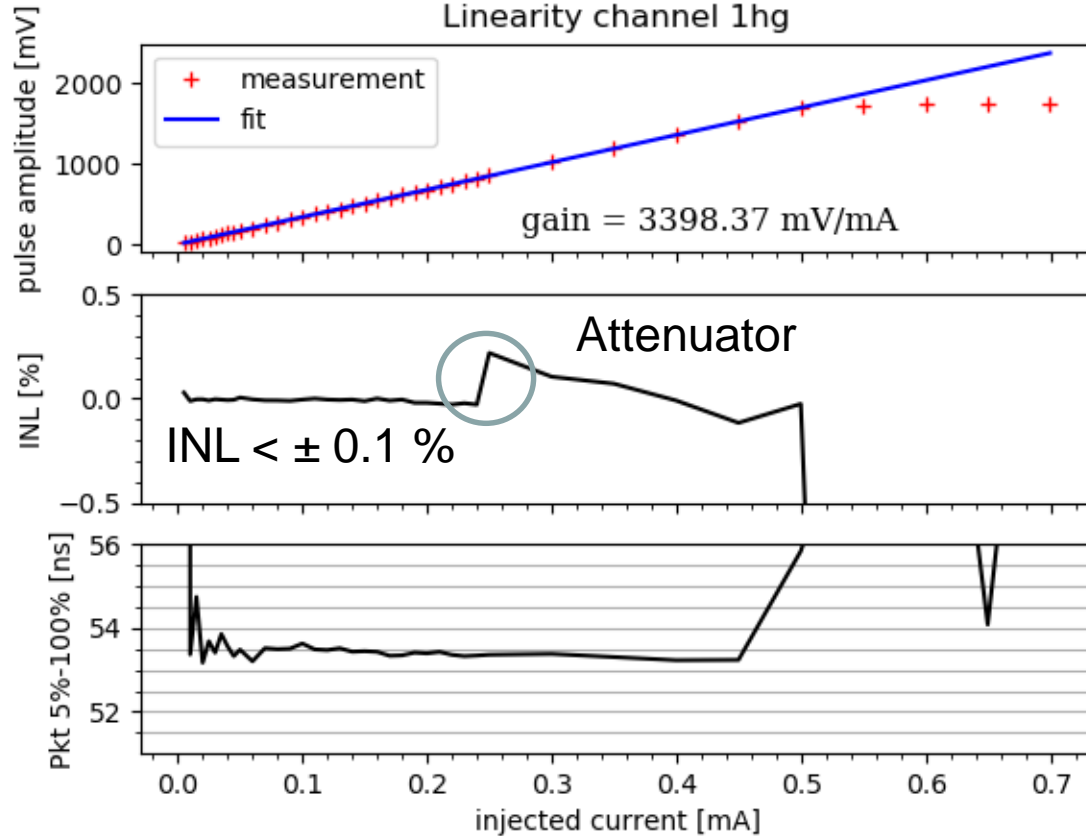
Specifications
 Linearity
 INL < $\pm 0.2\%$ on High Gain output
 INL < $\pm 0.5\%$ on 80% of Low Gain dynamic range
 INL < $\pm 3\%$ on the full dynamic range

HG

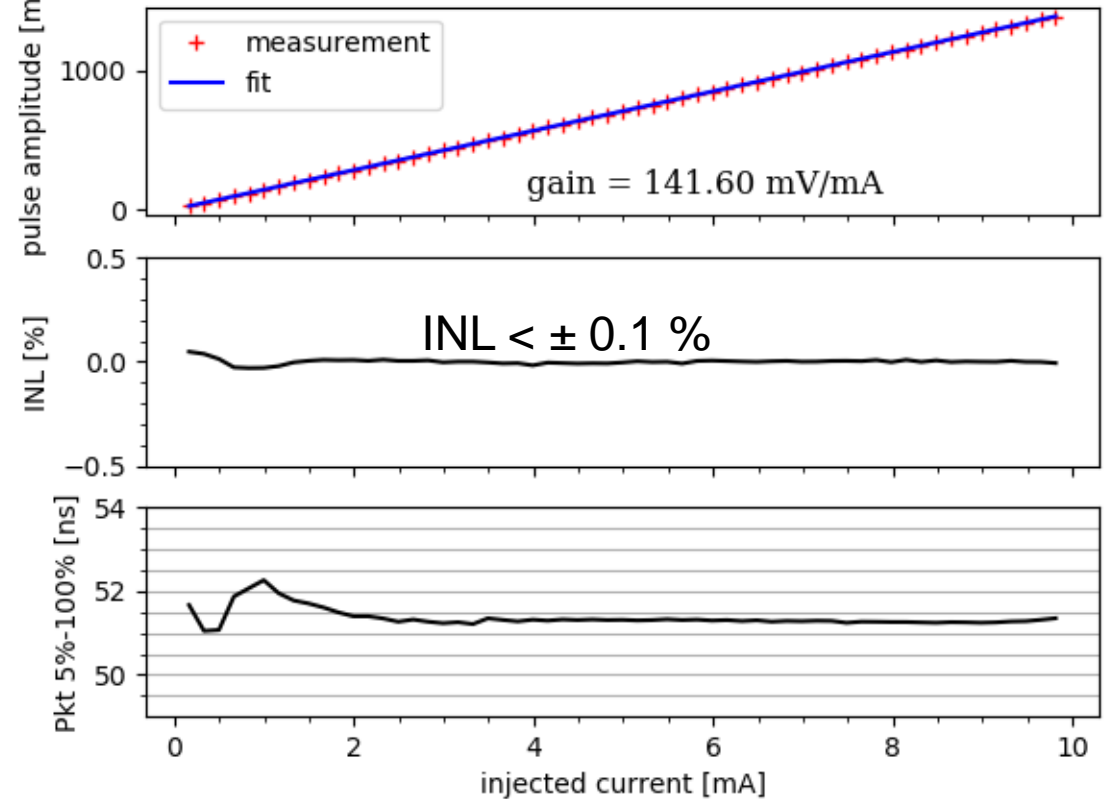
HG/LG ratio= 24

LG

Linearity channel 1hg



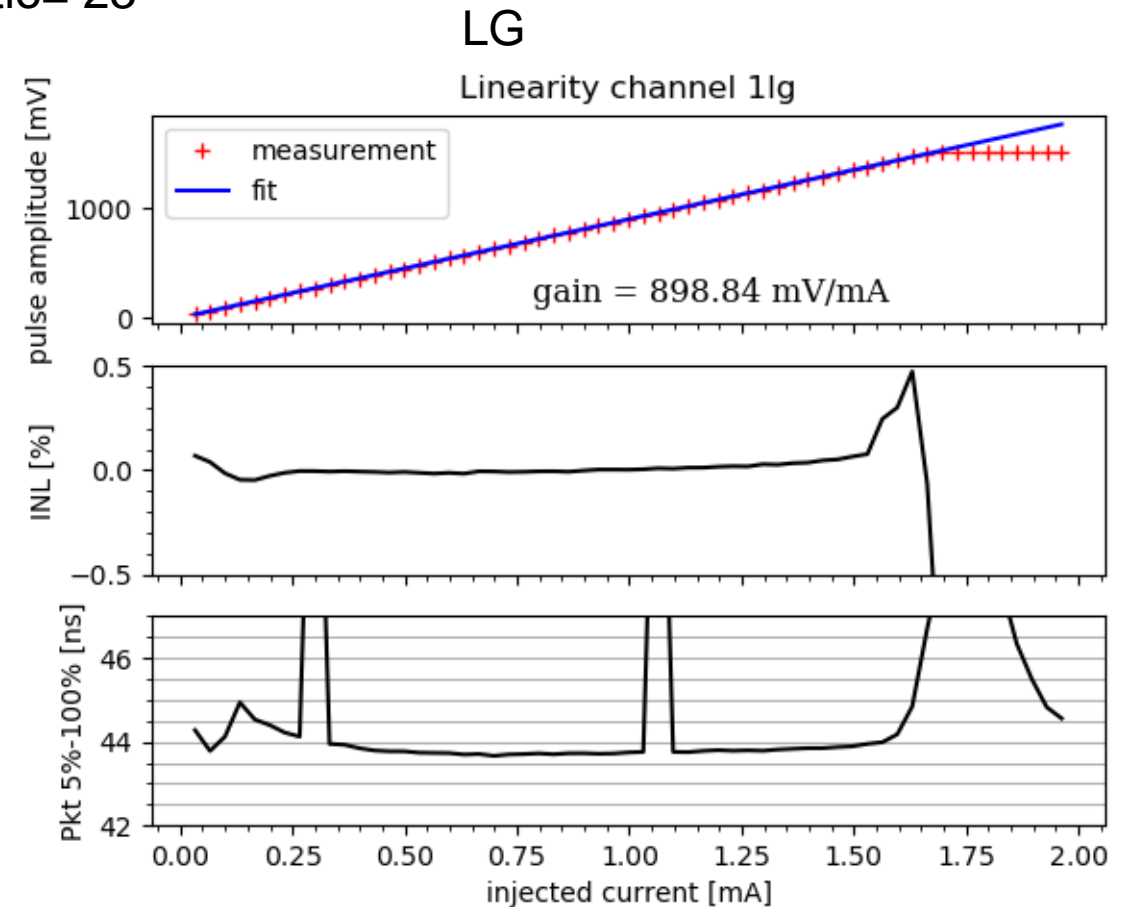
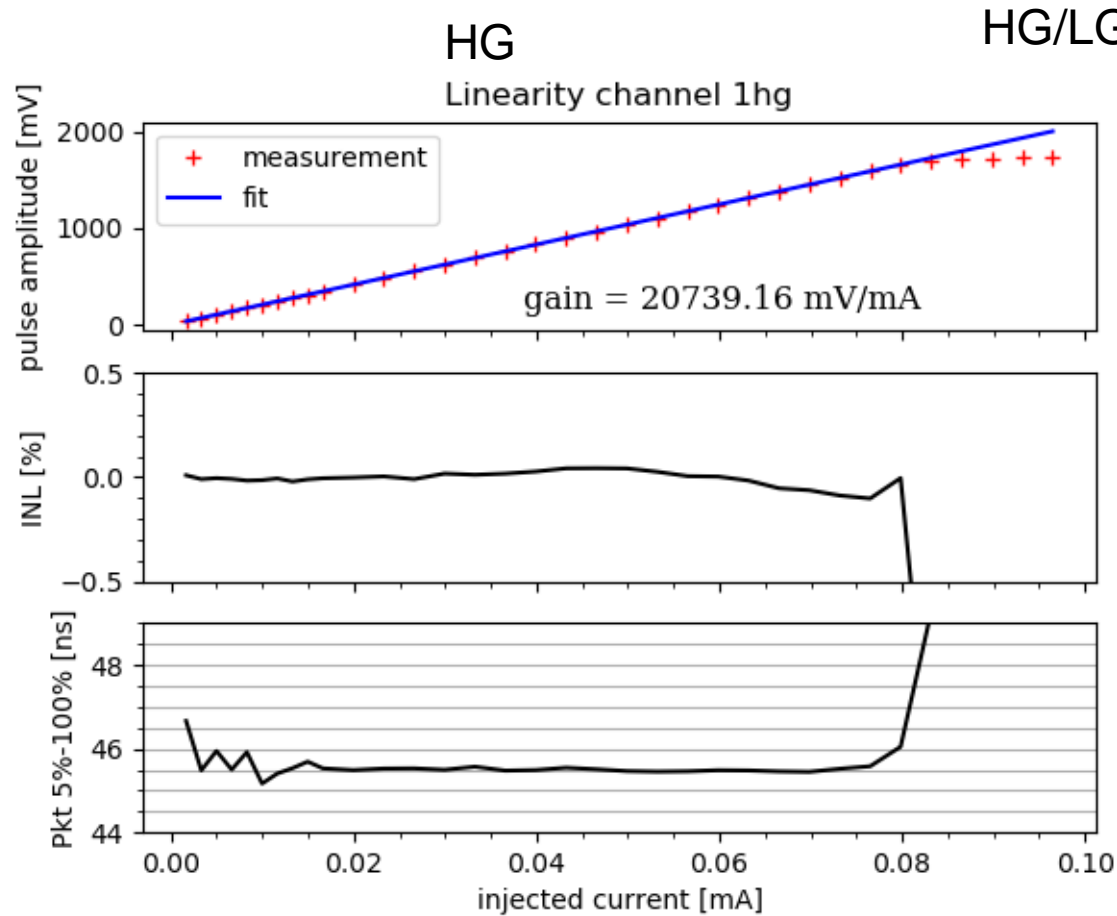
Linearity channel 1lg



Specifications

Linearity

- INL < $\pm 0.2\%$ on High Gain output
- INL < $\pm 0.5\%$ on 80% of Low Gain dynamic range
- INL < $\pm 3\%$ on the full dynamic range



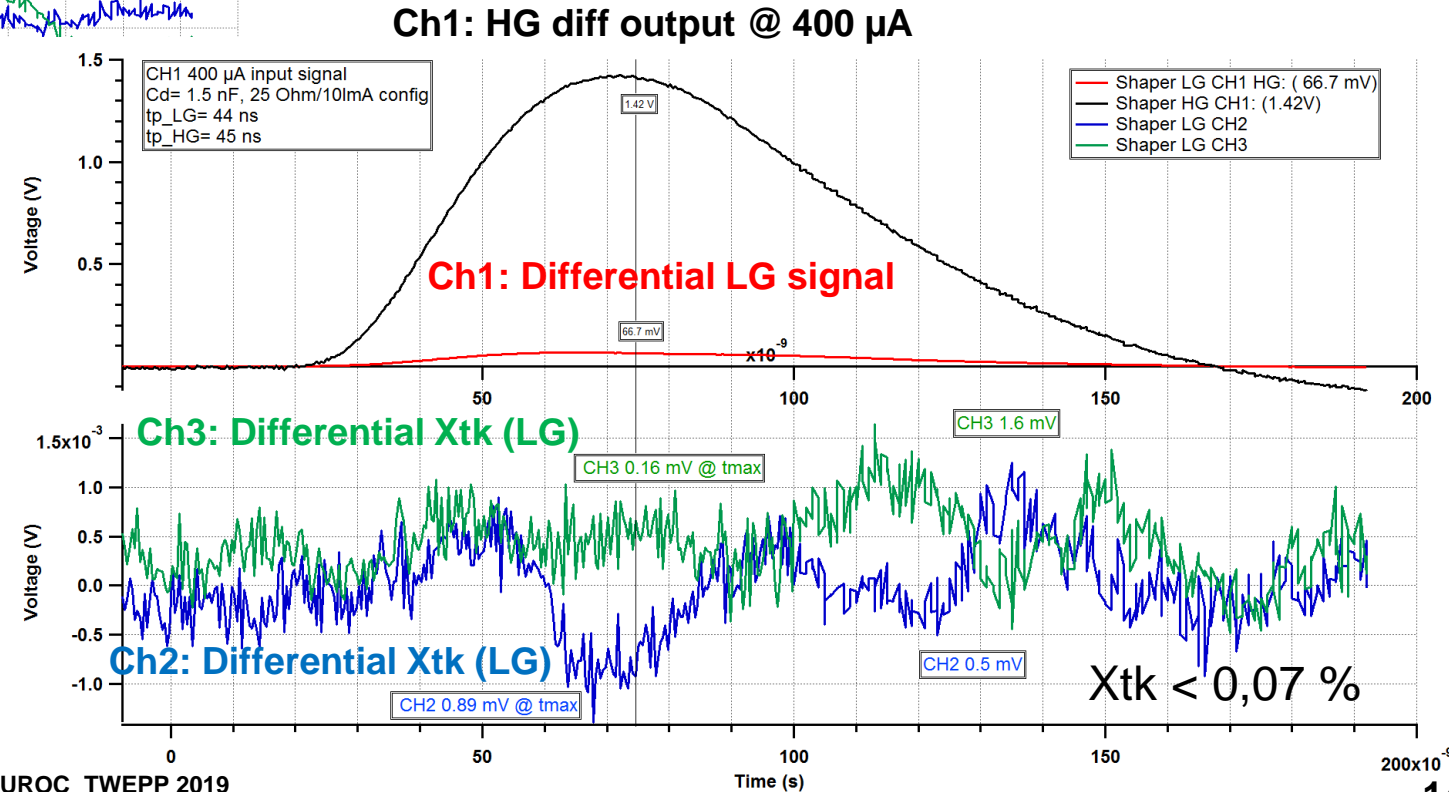
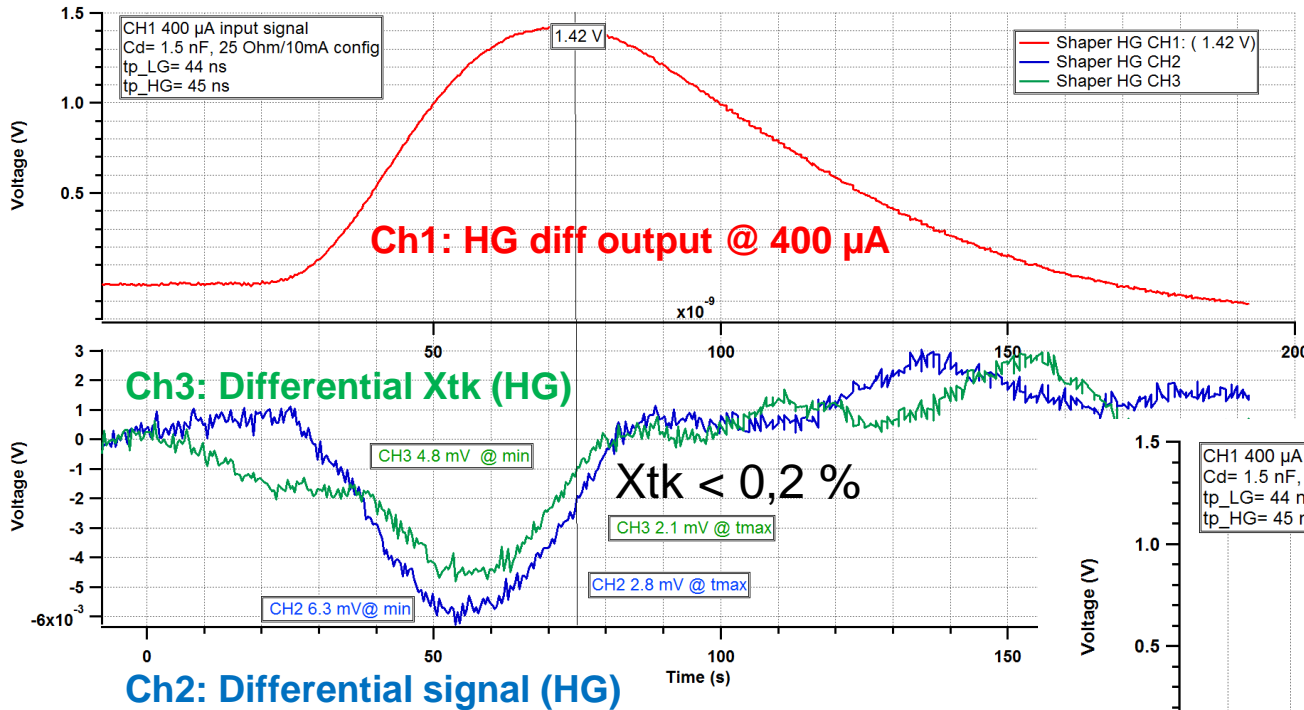
XTk (differential) between channels : 25 Ω 10 mA config

Injection of 400 μ A in ch1, Xt in Ch 2 and Ch3. Cd= 1.5 nF on all channels

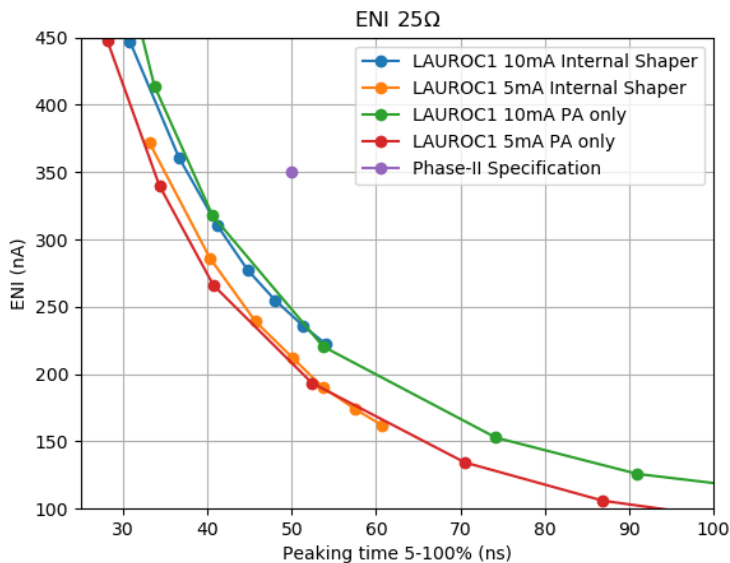
Specification:

Cross-talk

<0.5%



ENI vs tp 5-100% (injection of LArg pulses)



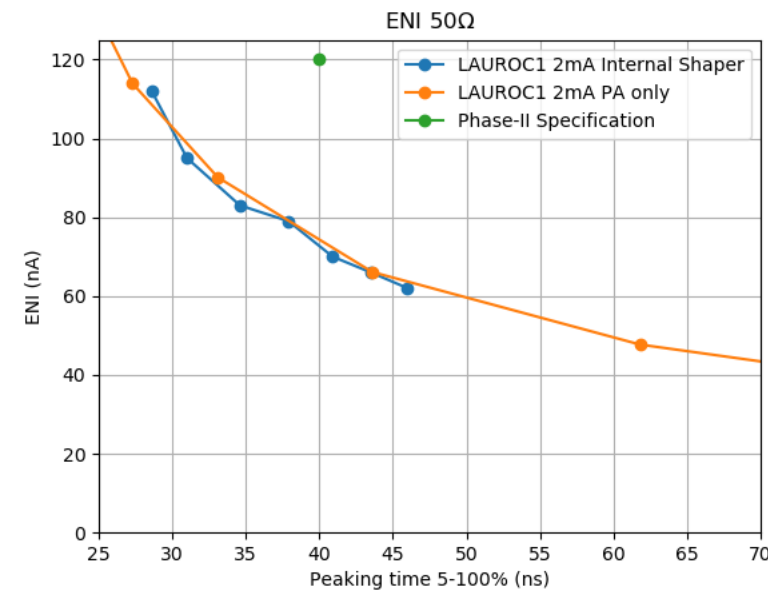
Specification:
 $< 300 \text{ nA @ } t_{p \text{ 5-100\%}} = 50 \text{ ns, } C_d = 1.5 \text{ nF}$ for 25 Ω config
 $< 120 \text{ nA @ } t_{p \text{ 5-100\%}} = 50 \text{ ns, } C_d = 330 \text{ pF}$ for 50 Ω config

LAUROC1 noise: below specification but larger than expected by 20%
 Series noise as expected : $e_n = 0.45 \text{ nV}/\sqrt{\text{Hz}}$ $C_{tot} = 36 \text{ pF}$ and parallel noise negligible, even with leakage current

But large 1/f noise (400 e-)

Attributed to dielectric noise in input $C_1 = 30 \text{ pF}$ MIM capacitor (goes as $4kT\omega C \tan\delta$): $\tan\delta$ of $\text{SiO}_2 = 0,002 \Rightarrow 278 \text{ e-}$

Special channel added in LAuroc2 with external capacitor for C_1 to prove it definitively

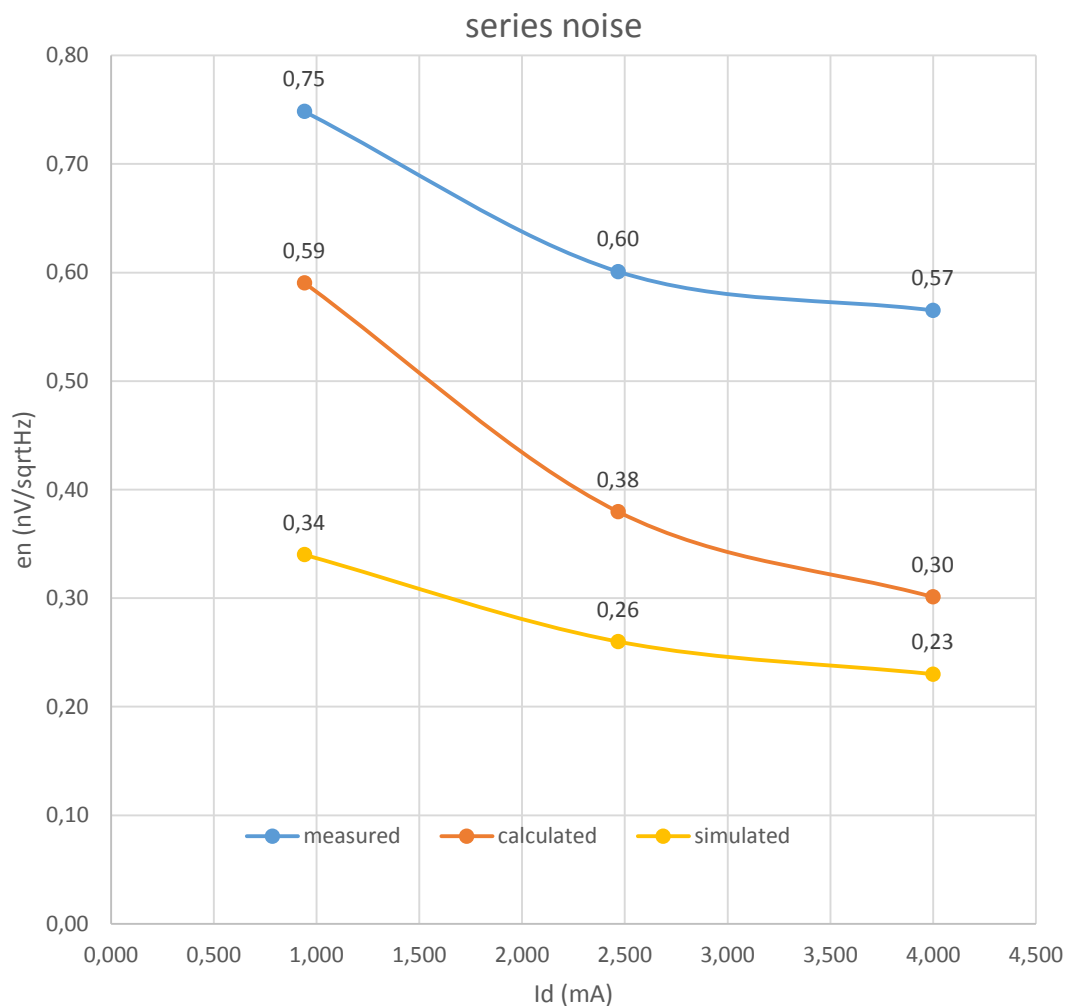


Series noise input transistor

3000/0.25 μm transistor at $I_D=4 \text{ mA}$

Measurement = 2 * theory

Simulation < theory !

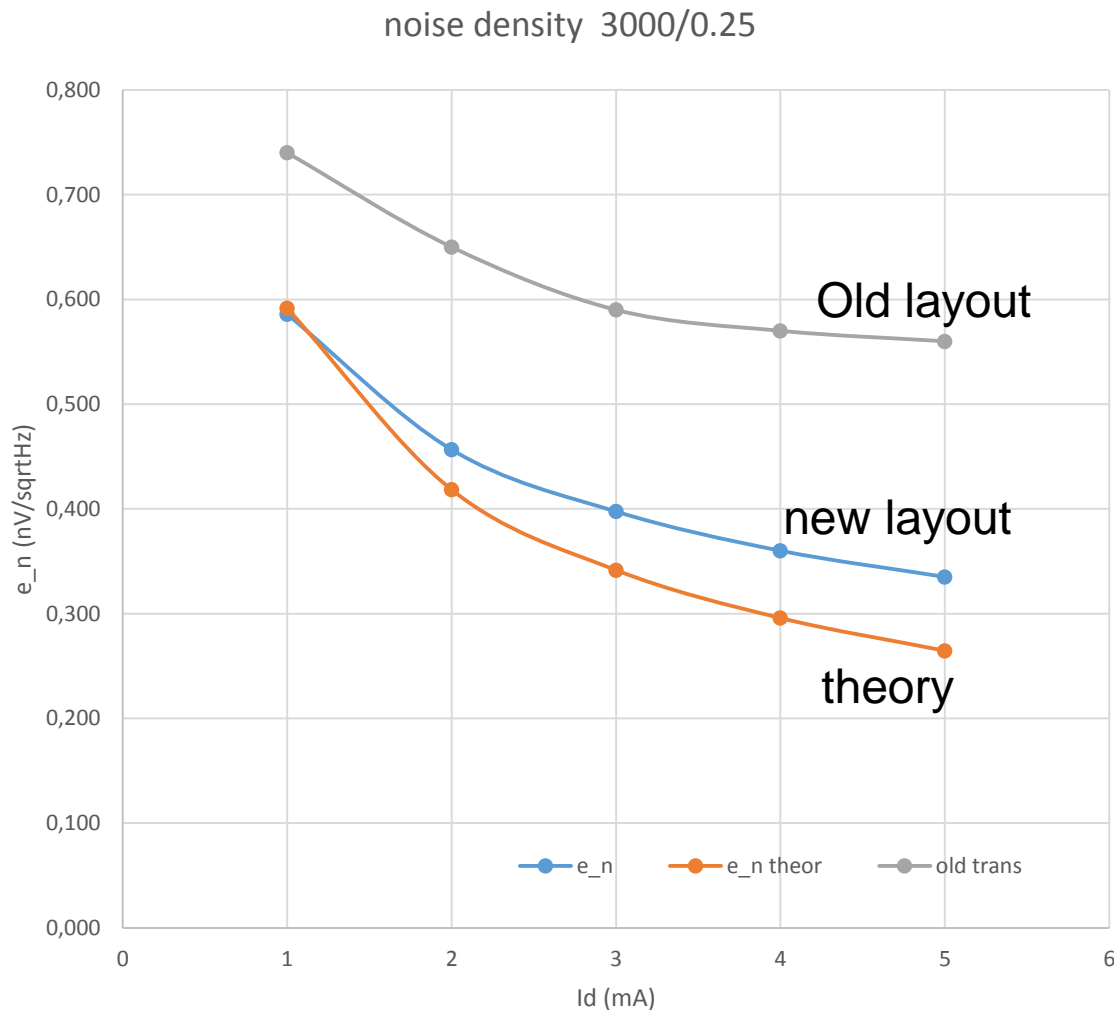


New layout with minimized bulk contribution

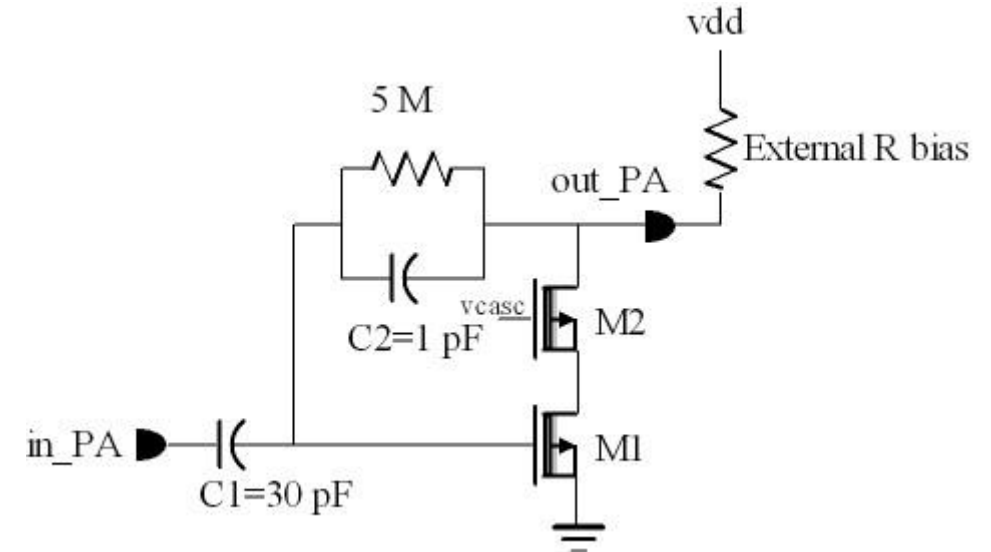
Measured noise now at 0.36 nV/ $\sqrt{\text{Hz}}$

close to calculations = 0.3nV (0.56nV before)

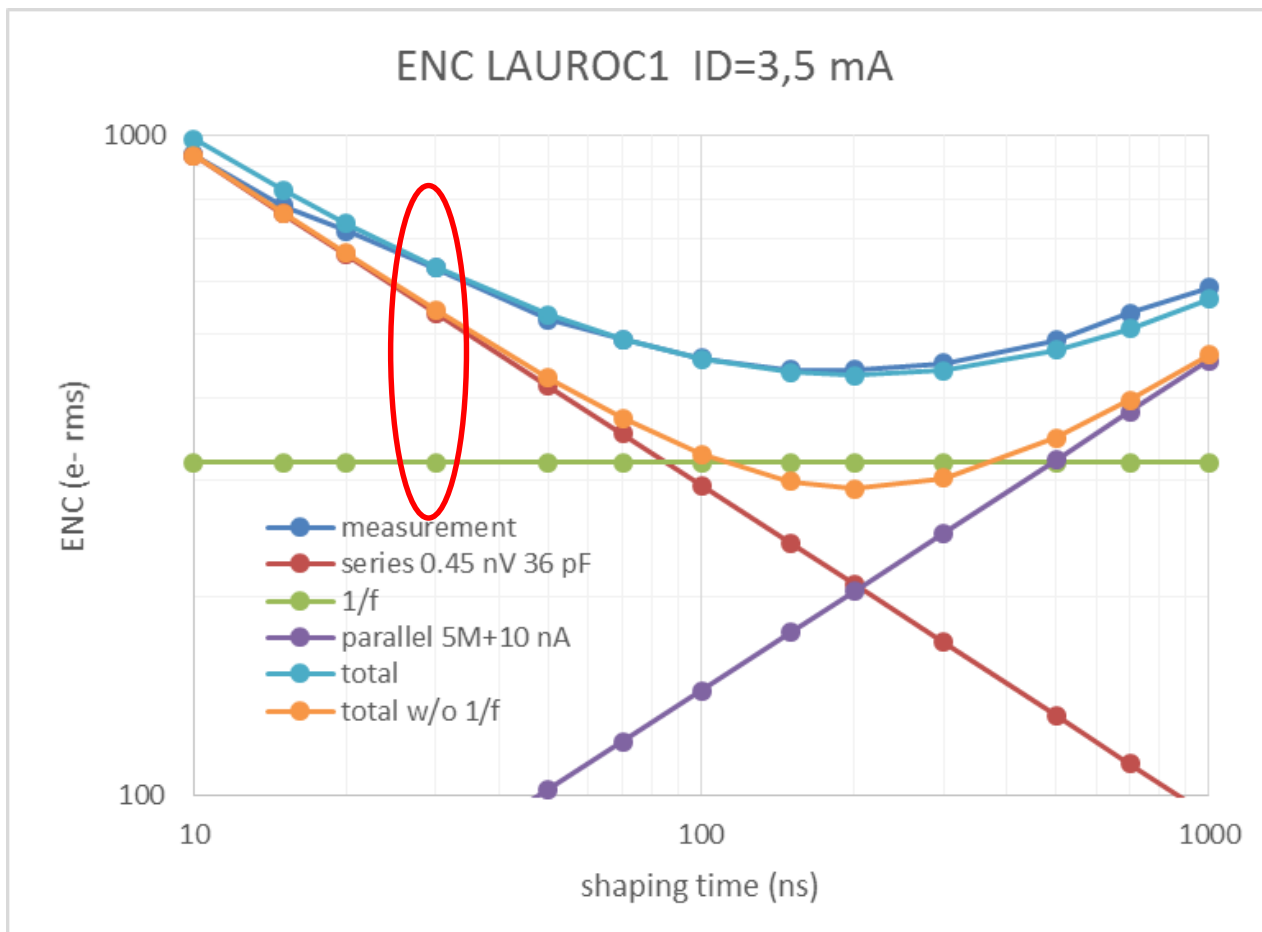
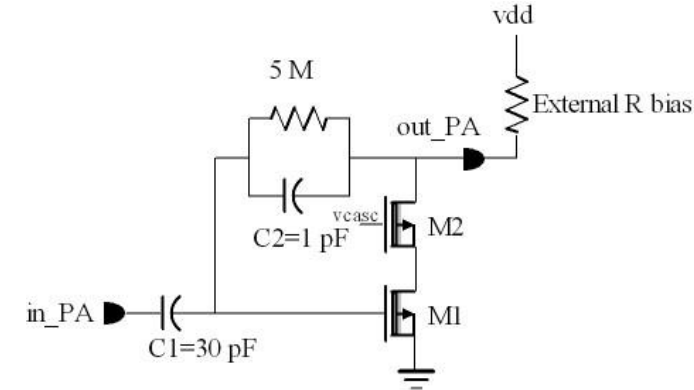
Difference corresponds to 0.2 nV/ $\sqrt{\text{Hz}}$ $\sim 2 \Omega$



- LAUROC1: Low noise input preamp measured alone as charge preamp followed by external variable CRRC² shaper. $C_f = 1$ pF
 - All current sources switched off : preamp biased externally by external RL
 - Noise expected : $ENC = 174 e_n C_{tot} / \sqrt{t_p} (\delta) \oplus 166 i_n \sqrt{t_p} (\delta)$
 - Parallel noise due to $R_f = 5$ M and leakage current, measured $I_G = 10$ nA

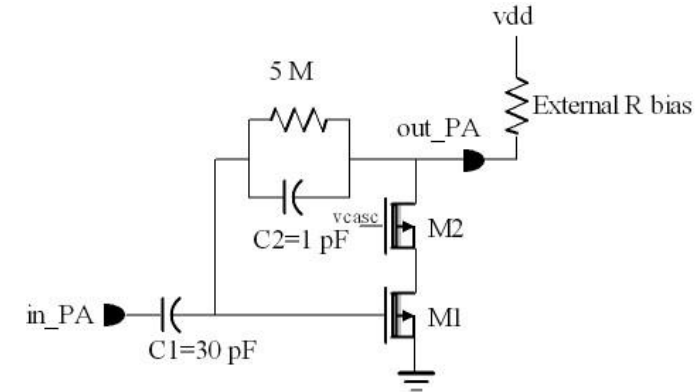


- Good agreement for series noise : $e_n = 0.45 \text{ nV}/\sqrt{\text{Hz}}$ $C_{\text{tot}}=36 \text{ pF}$
- Parallel noise negligible, even with leakage current
- But large unexpected 1/f noise (400 e-)
- At ATLAS shaping ($t_p = 30 \text{ ns}$) 1/f increases noise by ~20%

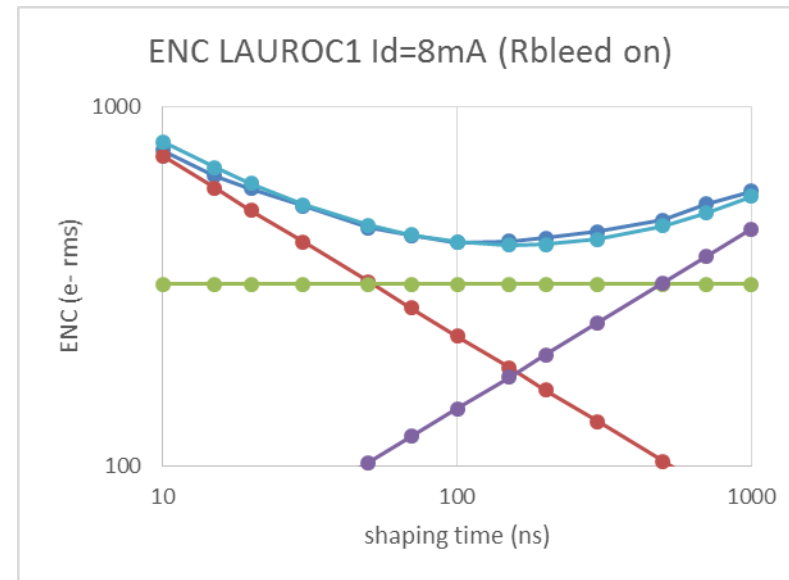
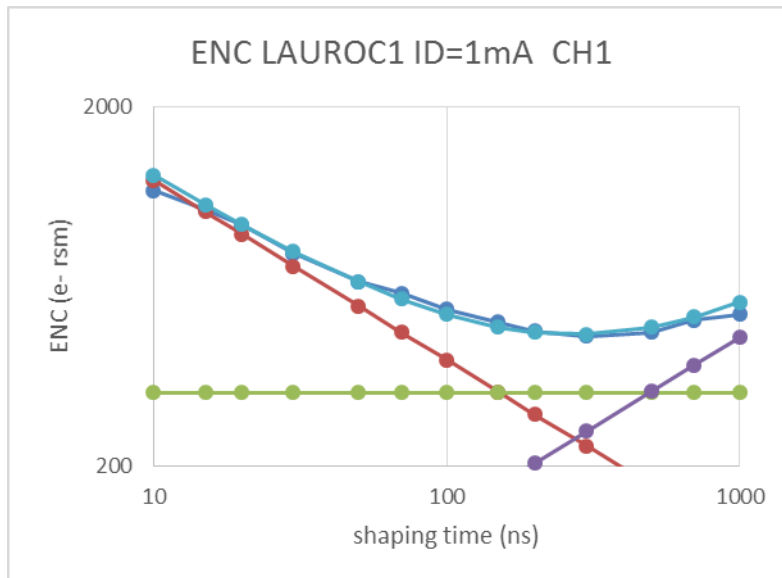


$$ENC = 174 e_n C_{\text{tot}} / \sqrt{t_p} (\delta) \oplus 166 i_n \sqrt{t_p} (\delta)$$

- 1/f can originate from the 2 transistors or the MIM cap
- Negligible 1/f measured on input transistor
- 1/f at the same level on CH4 which does not have 2.5V cascode
⇒ remains dielectric noise in the MIM input capacitor

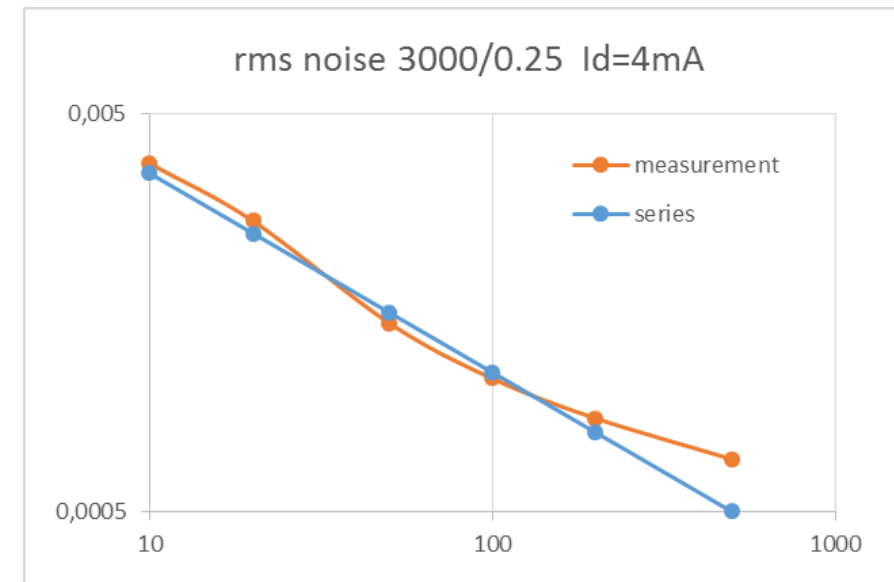
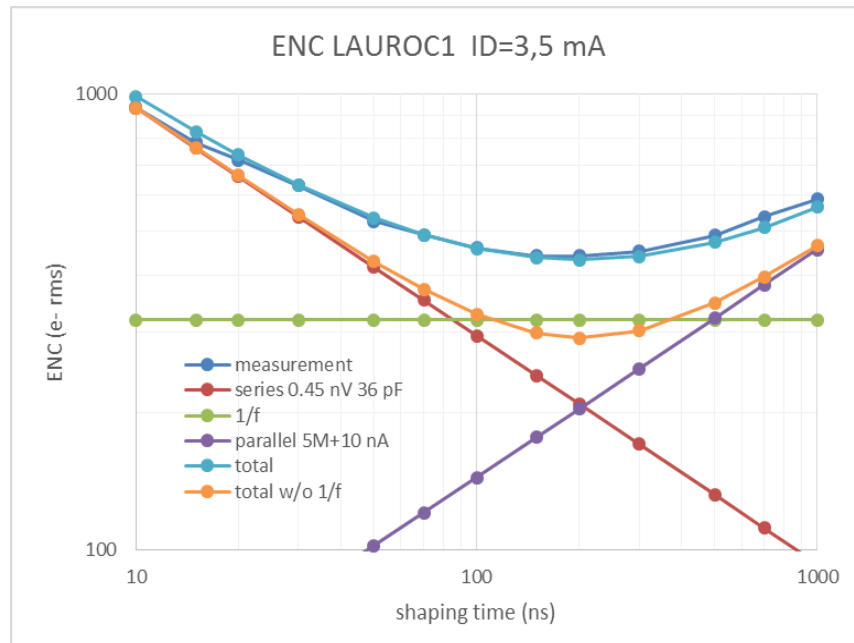


- Confirmed by measurement at small and large currents which shows 1/f unchanged
 - At 1 mA series noise plotted $e_n = 0.6 \text{ nV}/\sqrt{\text{Hz}}$
 - At 8 mA $e_n = 0.35 \text{ nV}/\sqrt{\text{Hz}}$



1/f input transistor alone

- ENC CH4 (1 V cascode)
- Input transistor alone (from previous run)
- Dielectric noise is parallel noise going as $4kT\omega C \tan\delta$
- $\tan\delta$ of SiO₂ = 0,002 => 278 e-, not far from the 320 e- given by the fit

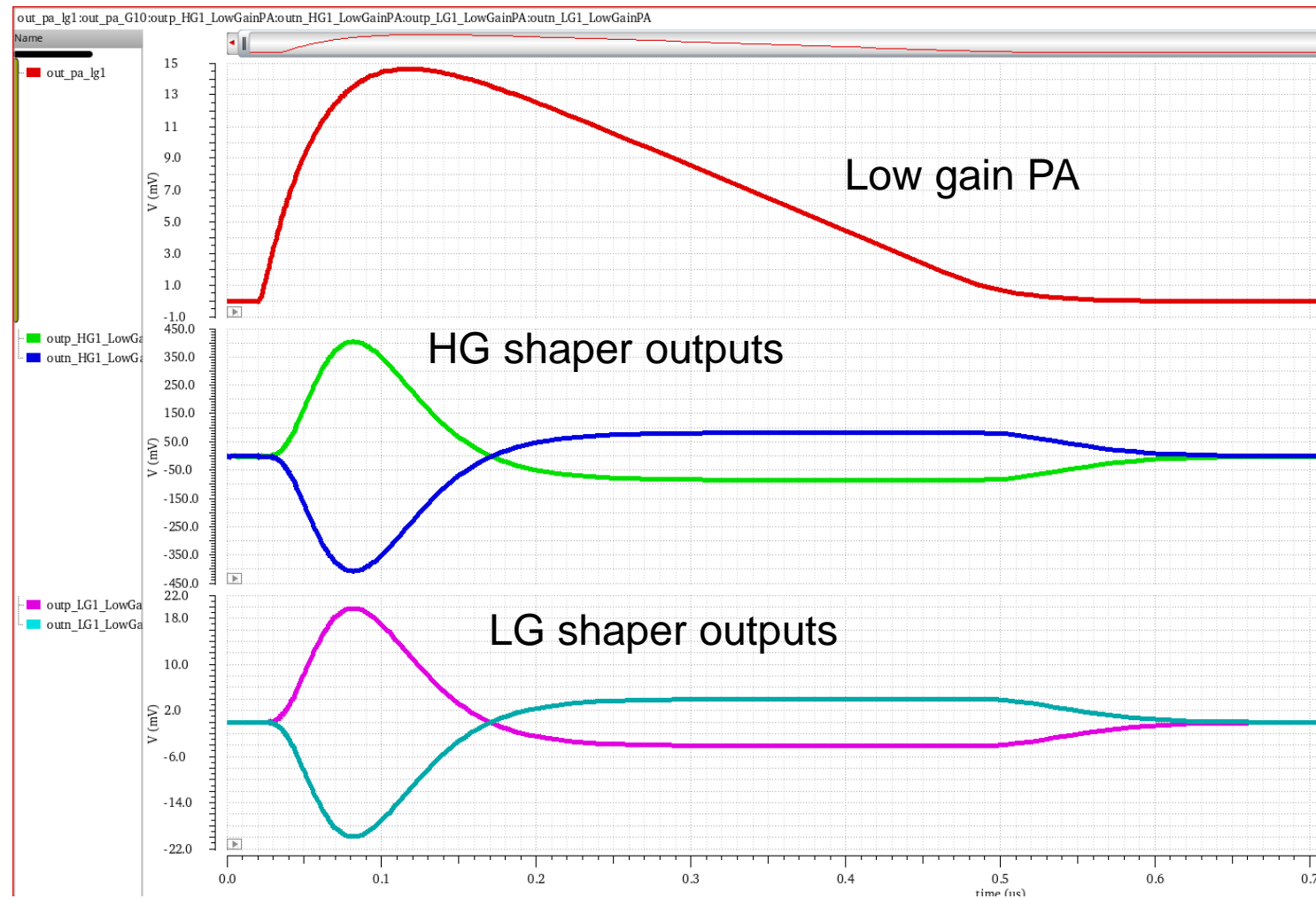


- Noise measurements on preamp alone show good agreement with theoretical noise
- Series noise :
 - $e_n = 0.6 \text{ nV}/\sqrt{\text{Hz}}$ @ 1 mA
 - $e_n = 0.45 \text{ nV}/\sqrt{\text{Hz}}$ @ $I_d = 4 \text{ mA}$
 - $e_n = 0.35 \text{ nV}/\sqrt{\text{Hz}}$ @ $I_d = 8 \text{ mA}$
 - Total capacitance 36 pF : 10% parasitics in MIM + input transistor
- Parallel noise :
 - $i_n = 0.09 \text{ pA}/\sqrt{\text{Hz}}$ due to $R_f=5\text{M}$ and 10 nA gate leakage current
 - Larger than expected but still negligible
- But large 1/f contribution
 - Independent of drain current or cascode type
 - Not seen on input transistor alone
 - **Attributed to dielectric noise in input 30 pF MIM capacitor** (goes as $4kT\omega C \tan\delta$): $\tan\delta$ of $\text{SiO}_2 = 0,002 \Rightarrow 278 \text{ e-}$, not far from the 320 e- given by the fit
 - Increases series noise by ~20%
 - Would need a special channel with external capacitor to prove it definitively

- Good performance for impedance matching and linearity
- Noise models were wrong for large transistors and large current : go back to BSIM3 model [J. Kaplon]
- Non negligible $1/f$ noise attributed to MIM caps
- Interesting design lower noise at BNL with fully differential amplifier [ALFE M. Dabrovski et al.]
- Final versions of LAUROC and ALFE submitted in sept.

- ATLAS at USC :





LG_Preamp_25_50, followed by a low noise amplifier with a gain=20 for the HG path
=> Shaper noise negligible

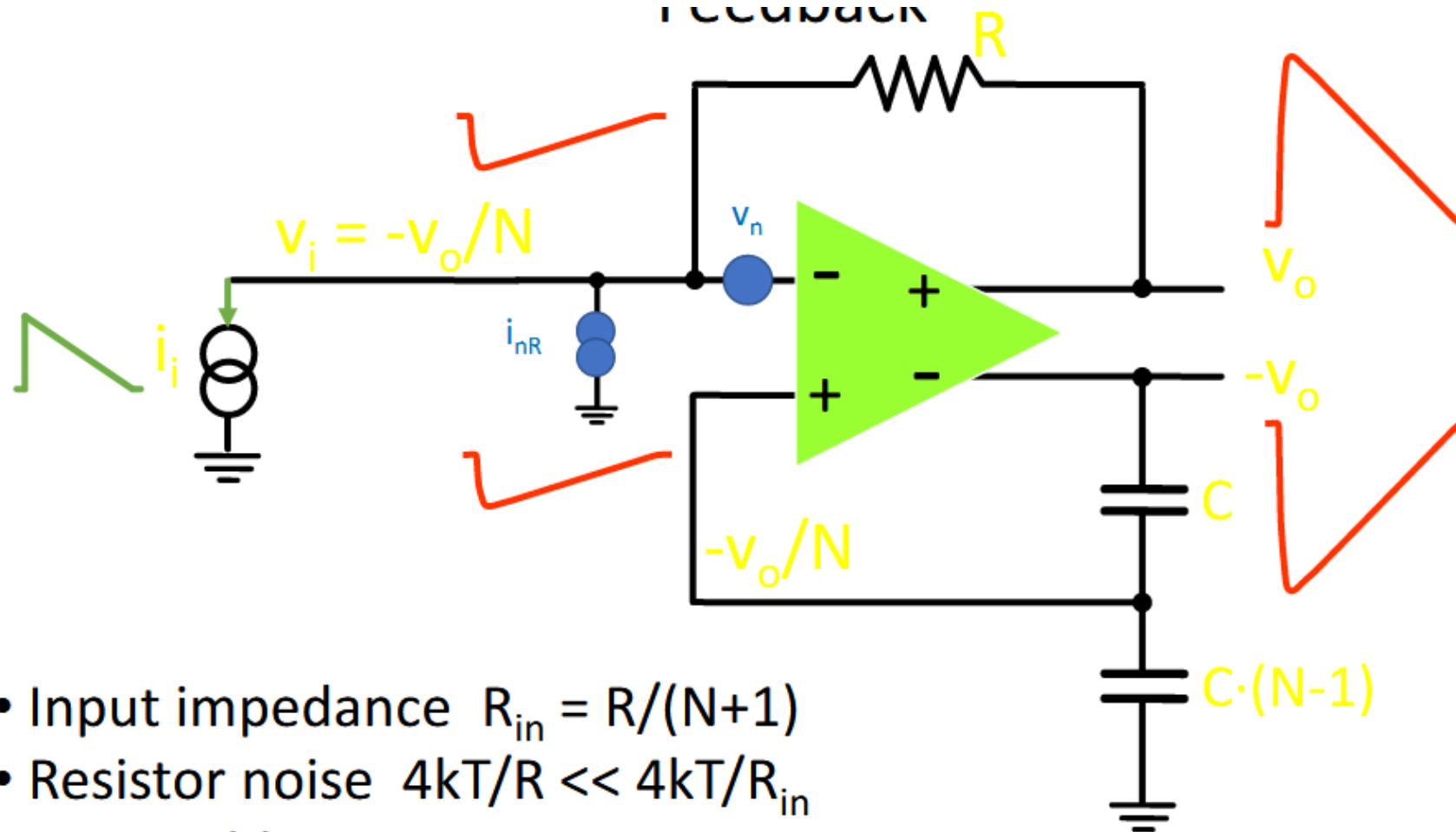
Dynamic range of the 25 Ω preamp tuneable by SC: 5 mA or 10 mA

Clod ADC= 20 pF

Simulations @ $\tau=15$ ns

Ratio HG/LG ≈ 25

- **LG_preamp 25 Ω with a dynamic range of 5 mA (tuned by SC), Cd=1.5 nF**
 - HG path: 250 μ A give ± 983 mV, $t_p= 46.5$ ns and **ENI= 167 nA**
 - LG path: 5 mA give ± 988 mV, $t_p=46$ ns
- **LG_preamp 25 Ω with a dynamic range of 10 mA (tuned by SC), Cd=1.5 nF**
 - HG path: 500 μ A give ± 930 mV, $t_p= 46$ ns and **ENI= 220 nA**
 - LG path: 10 mA give ± 920 mV, $t_p= 46$ ns
- **LG_preamp 50 Ω with a dynamic range of 2 mA, Cd=400 pF**
 - HG path: 75 μ A give ± 945 mV, $t_p= 48$ ns and **ENI= 53 nA**
 - LG path: 2 mA give ± 923 mV , $t_p= 46$ ns



- Input impedance $R_{in} = R/(N+1)$
- Resistor noise $4kT/R \ll 4kT/R_{in}$
- Very stable termination (R, N indep. of signal current and active components)
- Fully-differential output